JOS DiBell #3

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of:

David A. Cathey

Serial No.:

Filed:

January 12, 2001

For:

ELECTRON EMITTERS AND METHOD

FOR FORMING THEM

Commissioner for Patents

Washington, D.C. 20231

Group Art Unit:

Examiner:

88888

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92-0466.04

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INFORMATION DISCLOSURE STATEMENT

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I HEREBY CERTIFY THAT THIS PAPER IS BEING DEPOSITED WITH THE UNITED STATES POSTAL SERVICE "EXPRESS MAIL POST OFFICE TO ADDRESSEE" SERVICE UNDER 37 C.F.R § 1.10 ON THE DATE INDICATED ABOVE AND S ADDRESSED TO THE ASSISTANT

COMMISSIONER FOR PATENES, WASHINGTON, D.C. 2023

Signature

Dear Sir:

In compliance with the duty of disclosure under 37 C.F.R. § 1.56, Applicant respectfully requests that this Information Disclosure Statement be entered and that the references listed on the attached Form PTO-1449 be considered by the Examiner and made of record. Copies of the listed references are enclosed for the convenience of the Examiner.

In accordance with 37 C.F.R. § 1.97(b), this Information Disclosure Statement is not to be construed as a representation that a search has been made or that no other possible material information as defined in 37 C.F.R. § 1.56(a) exists.

The following references are submitted for the Examiner's review:

U.S. Patents

U.S. Patent No.	Issue Date	Inventor
6,049,089	04/11/00	Cathey
5,786,659	07/28/98	Takagi et al.
5,662,815	09/02/97	Kim
5,583,393	12/10/96	Jones
5,532,177	07/02/96	Cathey
5,469,014	11/21/95	Itoh et al.
5,431,777	07/11/95	Austin et al.
5,378,658	01/03/95 -	Toyoda et al.
5,372,973	12/13/94	Doan et al.
5,358,908	10/25/94	Reinberg et al.
5,330,920	07/19/94	Soleimani et al.
5,315,126	05/24/94	Field
5,269,877	12/14/93	Bol
5,201,992	04/13/93	Marcus et al.
5,138,220	08/11/92	Kirkpatrick
5,090,932	02/25/92	Dieumegard et al.
5,063,327	11/05/91	Brodie et al.
4,968,382	11/06/90	Jacobson et al.
4,964,946	10/23/90	Gray et al.
4,943,343	07/24/90	Bardai et al.
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4,420,872	12/20/83	Solo de Zaldivar
4,400,866	08/30/83	Yeh et al.
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3,812,559	05/28/74	Spindt et al.
3,755,704	08/28/73	Spindt et al.
3,665,241	05/23/72	Spindt et al.

Foreign Patents

3-238729	10/24/91	Sawai
57-43412	03/11/82	Kotani

Other References:

Hunt, Charles E., Johann T. Trujillo, William J. Orvis, "Structure and Electrical Characteristics of Silicon Field-Emission Microelectronic Devices," IEEE Transactions on Electron Devices, Vol. 38, No. 10, October 1991.

Marcus, R. B., T. S. Ravi, T. Gmitter, H. H. Busta, J. T. Niccum, K. K. Chin, and D. Liu, "Atomically Sharp Silicon and Metal Field Emitters," IEEE Transactions on Electron Devices, Vol. 38, No. 10, October 1991.

Wolf, Stanley, SILICON PROCESSING FOR THE VLSI ERA, Volume 2: Process Integration, Lattice Press, Sunset Beach, California, pp. 20-27, 1990.

Jones, G. W. and C. T. Sune, "Fabrication of Silicon Point, Wedge, and Trench FEAs", Technical Digest of IVMC 91, Nagahama 1991, pp 34-35.

Millman, J. et al., <u>Integrated Electronics: Analog and Digital Circuits and System</u>, pp. 204-205, 1972 (no month).

As this information is being submitted within three months of the date of filing of the application, Applicant understands that no fee or certification is required for the submission and consideration of this information at this time.

If there are any matters which may be resolved or clarified through telephone interview, the Examiner is respectfully requested to contact Applicant's undersigned attorney at the number indicated.

* * * *

A Form PTO-1449 is enclosed herewith.

Respectfully submitted,

Date: 1/12[1

Charles B. Brantley
Reg. No. 38,086
Micron Technology, Inc.
8000 S. Federal Way
Boise, ID 83716-9632
(208) 368-4557
ATTORNEY FOR APPLICANT